Electronic Supplementary Information (ESI)

Crystal surface defects as possible origins of cocrystal dissociation

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1. Experimental section

Samples were analysed using a Nanoscope Multimode AFM (Veeco Instruments, Cambridge, UK). Samples were imaged in air under ambient conditions using intermittent contact mode with a J scanner (180 μ m² maximum scan size), together with MikroMasch NSC15 SPM probes which had a typical force constant of 40 Nm⁻¹ and tip radius of 10 nm (MikroMasch, 2008). The tapping force which was applied to the probe while imaging was kept to a minimum to prevent the tip from damaging the sample surface. The typical scan area was 5 μ m² (resolution of 256 lines), recorded at a scan rate of 1 Hz per line. Images were processed using Nanoscope Analysis v1.40 and a first order flattening correction was applied.



Figure S1. Axial distance (nm, y-axis) vs. time (s, x-axis) during molecular diffusion across the four faces with different rate at 0 % RH.



Figure S2. IC-AFM height images of Form II (Area 1) at 40% humidity. Screw dislocation inducing molecular diffusion can be observed as the rectangular groove across the surface.



Figure S3. Axial distance (nm, y-axis) vs. time (s, x-axis) during molecular diffusion across the four faces with different rate (Area 1) at 40% humidity.



Figure S4. Axial distance (nm, y-axis) vs. time (s, x-axis) during crystal growth across the four faces with different growth rate (Area 3) at 40% RH.



Figure S5. IC-AFM height images of Form II (Area 4) at 70% RH show two screw dislocation sites. White protrusions observed in image (f) are deposition of caffeine hydrate needles (blue cursor) on crystal surface based on our previous report.^{1, 2}



Figure S6. Axial distance (nm, y-axis) vs. time (s, x-axis) during molecular diffusion across the four faces (Area 4) with different rate at 70% RH (Upper layer, 1st unit).



Figure S7. Axial distance (nm, y-axis) vs. time (s, x-axis) during molecular diffusion across the four faces with different rate at 70% RH (Upper layer, 2nd unit beneath the 1st unit).



Figure S8. Axial distance (nm, y-axis) vs. time (s, x-axis) during molecular diffusion across the four faces with different rate at 70% RH (lower layer, 1st unit).



Figure S9. Axial distance (nm, y-axis) vs. time (s, x-axis) during molecular diffusion across the four faces with different rate at 70% RH (lower layer, 2nd unit beneath the 1st unit).

Reference

- 1. R. Thakuria, M. D. Eddleston, E. H. H. Chow, L. J. Taylor, B. J. Aldous, J. F. Krzyzaniak and W. Jones, *CrystEngComm*, 2016, **18**, 5296-5301.
- 2. R. Thakuria, M. Arhangelskis, M. D. Eddleston, E. H. H. Chow, K. K. Sarmah, B. J. Aldous, J. F. Krzyzaniak and W. Jones, *Org. Process Res. Dev.*, 2019, **23**, 845-851.